

Notice of References Cited	Application/Control No. 10/586,953		Applicant(s)/Patent Under Reexamination IIDA ET AL.	
	Examiner G. NAGESH RAO		Art Unit 1792	Page 1 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-3,036,017 A	05-1962	GUSTAV SCHREWELIUS NILS	252/516
*	B	US-4,659,421 A	04-1987	Jewett, David N.	117/21
*	C	US-4,842,686 A	06-1989	Davis et al.	438/709
*	D	US-4,935,046 A	06-1990	Uchikawa et al.	65/17.4
*	E	US-4,956,208 A	09-1990	Uchikawa et al.	428/34.6
*	F	US-5,067,989 A	11-1991	Yokota et al.	423/348
*	G	US-5,314,571 A	05-1994	Ciszek, Theodore F.	117/60
*	H	US-5,544,616 A	08-1996	Ciszek et al.	117/60
*	I	US-5,609,682 A	03-1997	Sato et al.	117/2
*	J	US-5,667,584 A	09-1997	Takano et al.	117/13
*	K	US-5,958,794 A	09-1999	Bruxvoort et al.	438/692
*	L	US-6,086,671 A	07-2000	Kawanishi et al.	117/30
*	M	US-2002/0024152 A1	02-2002	Momoi et al.	257/913

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/586,953		Applicant(s)/Patent Under Reexamination IIDA ET AL.	
	Examiner G. NAGESH RAO		Art Unit 1792	Page 2 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,344,083 B1	02-2002	Holder, John Davis	117/13
*	B	US-6,387,466 B1	05-2002	Fusegawa et al.	428/64.1
*	C	US-2002/0083887 A1	07-2002	Holder, John D.	117/13
*	D	US-6,447,601 B1	09-2002	Phillips et al.	117/13
*	E	US-6,458,204 B1	10-2002	Okui et al.	117/30
*	F	US-2003/0010276 A1	01-2003	Abe et al.	117/13
*	G	US-2003/0000457 A1	01-2003	Oda et al.	117/200
*	H	US-2003/0033972 A1	02-2003	Javidi, Massoud	117/13
*	I	US-2003/0024467 A1	02-2003	Phillips et al.	117/20
*	J	US-2003/0116082 A1	06-2003	Sakurada et al.	117/20
*	K	US-6,784,079 B2	08-2004	Wakamatsu et al.	438/507
*	L	US-6,858,076 B1	02-2005	Nakajima et al.	117/13
*	M	US-6,899,758 B2	05-2005	Abe et al.	117/13

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/586,953		Applicant(s)/Patent Under Reexamination IIDA ET AL.	
	Examiner G. NAGESH RAO		Art Unit 1792	Page 3 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0120945 A1	06-2005	Hansen, Richard L.	117/015
*	B	US-6,913,646 B2	07-2005	Sakurada et al.	117/13
*	C	US-2005/0247259 A1	11-2005	Yoon et al.	117/013
*	D	US-2006/0016387 A1	01-2006	Yokoyama et al.	117/084
*	E	US-2006/0130738 A1	06-2006	Kurita et al.	117/014
*	F	US-2006/0225639 A1	10-2006	Ono et al.	117/013
*	G	US-2007/0034138 A1	02-2007	Ono et al.	117/020
*	H	US-2007/0158653 A1	07-2007	Iida et al.	257/064
*	I	US-7,326,395 B2	02-2008	Fusegawa et al.	423/328.2
*	J	US-7,374,741 B2	05-2008	Ono et al.	423/328.2
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.